

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Kouichi WADA et al.

Art Unit :

Serial No.:

Examiner :

Filed :

Title : PROBE CARD AND METHOD FOR MANUFACTURING THEREOF

Assistant Commissioner for Patents
Washington, DC 20231

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T.B
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PRELIMINARY AMENDMENT

Prior to consideration of this application, please amend the claims as follows. Please consider the application in light of these amendments and the included remarks.

IN THE CLAIMS:

Please amend the following claims as indicated (a marked up version of the claims appears in Appendix A, in accordance with 37 C.F.R. §1.121(c)(1)(ii)):

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- 1 3. (Amended) A probe card as claimed in claim 1, wherein said contactor is extended to
2 a predetermined direction from a surface of said substrate.
- 1 4. (Amended) A probe card as claimed in claim 1, wherein said contactor has a vertical
2 elasticity against a surface of said substrate.
- AI 1 5. (Amended) A probe card as claimed in claim 1, wherein at least a portion of said
2 signal transmission path near said end of it is made of the same amorphous material used for
3 said contactor.
- 1 6. (Amended) A probe card as claimed in claim 1 further comprising a grounding line,
2 which is grounded, formed to be apart from and in parallel to said signal transmission path.